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DATE MAILED: 04/21/2006

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/633,055	07/31/2003	Shahriar Ahmed	42P10970C	3607
7:	590 04/21/2006		EXAM	INER
Michael A. Bernadicou			IM, JUNGHWA M	
BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP 12400 Willshire Boulevard Seventh Floor, CA 90025			ART UNIT	PAPER NUMBER
			2811	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
	10/633,055	AHMED ET AL.				
Office Action Summary	Examiner	Art Unit				
	Junghwa M. Im	2811				
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address				
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	nely filed s will be considered timely. the mailing date of this communication. O (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on 15 M	arch 2006.					
2a) ☐ This action is FINAL . 2b) ☒ This						
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is						
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claims						
4) Claim(s) 13,17-22 and 27-31 is/are pending in	the application.					
4a) Of the above claim(s) is/are withdrawn from consideration.						
5) Claim(s) is/are allowed.						
6) Claim(s) is/are rejected.						
7) Claim(s) <u>13,17-22 and 27-31</u> is/are objected to						
8) Claim(s) are subject to restriction and/or	election requirement.					
Application Papers						
9)☐ The specification is objected to by the Examine	r.					
10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.						
Applicant may not request that any objection to the	drawing(s) be held in abeyance. See	37 CFR 1.85(a).				
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).						
11) The oath or declaration is objected to by the Ex	aminer. Note the attached Office	Action or form PTO-152.				
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documents	s have been received.					
2. Certified copies of the priority documents	• •					
 Copies of the certified copies of the prior application from the International Bureau 	·	d in this National Stage				
* See the attached detailed Office action for a list of	• • • • • • • • • • • • • • • • • • • •	d				
See the diagness detailed entire detail for a list (or the definition depicts flot receive	~ .				
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview Summary	(PTO-413)				
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/Mail Da	te				
3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	5) Notice of Informal P 6) Other:	atent Application (PTO-152)				

DETAILED ACTION

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 13, 17-22 and 27-31 are rejected under 35 U.S.C. 103(a) as being unpatentable over Akbar et al. (U.S. Pat. No. 4957875), hereinafter Akbar in view of Harame et al. (U.S. Pat. No. 5024957), hereinafter Harame.

Regarding claim 13, Fig. 8 of Akbar shows a bipolar junction transistor comprising: in a substrate 32, a first isolation structure 36 spaced apart from a second isolation structure 38;

a base 14, 22 formed in the substrate;

an emitter stack 16 disposed above the substrate and between the first isolation structure and the second isolation structure;

a recess (a portion between the regions 17, 18) disposed immediately adjacent to the emitter stack and disposed between the emitter stack and the first isolation structure, wherein the recess exposes a collector tap 26, wherein the emitter stack and the recess share a boundary; and

an emitter cut (an emitter/base junction) provide at the bottom of said emitter stack and on top of an intrinsic base structure (a portion of the base in contact with the emitter) formed in the substrate.

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Fig. 8 of Akbar shows most aspect of the instant invention except an intrinsic base formed in the epitaxial base. Fig. 9 of Harame shows a semiconductor device wherein an intrinsic base 32 formed in the epitaxial base 32A (col. 4, lines 10-16) is formed in the substrate. It would have been obvious to one of ordinary skill in the art at the time of the invention to incorporate the teachings of Harame into the device of Akbar in order to have an intrinsic base in the epitaxial base formed in the substrate to alleviate the leakage current.

Note that "epitaxial" is a process designation, and would not carry patentable weight in this claim drawn to a product. See *In re Thorp*, 227 USPQ 964 (Fed. Cir. 1985).

Regarding claim 17, Fig. 8 of Akbar shows a buried layer 34 in the substrate between the first isolation structure and the second isolation structure.

Regarding claim 18, Fig. 8 of Akbar shows a bipolar junction transistor further including: a collector structure 12 disposed in the substrate below the emitter stack; and an intrinsic base structure 14 disposed between the emitter stack 16 and the collector structure 12.

Regarding claim 19, Fig. 8 of Akbar shows a bipolar junction transistor further including: a collector structure 12 disposed in the substrate below the emitter stack; and a dielectric layer 18, 20 disposed above the substrate and below the emitter stack and above the collector structure; and

an intrinsic base structure 14 disposed between the emitter stack and the collector structure.

Fig. 8 of Akbar shows most aspect of the instant invention except "the dielectric layer is patterned for said emitter cut to be formed therein." Fig. 9 of Harame shows a semiconductor

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device wherein the dielectric layer 34, 36 is patterned for the emitter cut (a bottom portion of the emitter 40) to be formed therein. It would have been obvious to one of ordinary skill in the art at the time of the invention to incorporate the teachings of Harame into the device of Akbar in order to have to a semiconductor device wherein the dielectric layer patterned for the emitter cut to reduce parasite capacitance between the emitter and the extrinsic base.

Regarding claim 20, Fig. 8 of Akbar shows a collector tap 26 is N type.

Regarding claim 21, Akbar discloses that the substrate includes a BiCMOS structure (col. 1, lines 11-14).

Regarding claim 22, Fig. 8 of Akbar shows the BJT is selected from a monojunction BJT device and a heterojunction BJT device.

Regarding claim 27, Fig. 8 of Akbar shows the collector tap 127 is self-aligned with the emitter stack.

Also, note that "self-aligned" is a process designation and would thus not carry patentable weight in this claim drawn to a product. See *In re Thorp*, 227 USPQ 964 (Fed. Cir. 1985).

Regarding claim 28, Fig. 8 of Akbar shows the bipolar junction transistor is an NPN transistor, and the collector tap is N type.

Regarding claim 29, Akbar discloses the bipolar junction transistor is an PNP transistor, and the collector tap is P type (col. 3, lines 24-25).

Regarding claim 30, Fig. 8 of Akbar shows the collector tap has no doping that is different from the substrate.

Regarding claim 31, Fig. 8 of Akbar shows the recess is a contact corridor.

Response to Arguments

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Applicant's arguments with respect to pending claims have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Junghwa M. Im whose telephone number is (571) 272-1655. The examiner can normally be reached on MON.-FRI. 8:30AM-5:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's acting supervisor, Eddie C. Lee can be reached on (571) 272-1732. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

jmi

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